

Search Notes

Application/Control No.

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Examiner

Alvin C. Chin-Shue

Applicant(s)/Patent under
Reexamination

BEAN ET AL.

Art Unit

3634

SEARCHED

Class	Subclass	Date	Examiner
182	2.1 →	6.20.05	AS
	2.11		
	63.1		
	69.6		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR